## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination NAKAYAMA ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0150243	10-2002	Craft et al.	380/201
	В	US-5,539,826	07-1996	Dwork et al.	713/169
	O	US-2003/0001743	01-2003	Menard, Raymond J.	340/573.1
	D	US-2003/0017826	01-2003	Fishman et al.	455/426
	Е	US-2003/0114106	06-2003	Miyatsu et al.	455/41
	F	US-2003/0163686	08-2003	Ward et al.	713/156
	G	US-2004/0139018	07-2004	Anderson et al.	705/041
	Ή	US-2005/0044191	02-2005	Kamada et al.	709/223
	-	US-2003/0227934	12-2003	White et al.	370/432
	-	US-			
	К	US-			
·	٦	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.